



PATENT

In the United States Patent and Trademark Office

Applicants: Linda BRALY et al.)
Applicants' Reference: LAM2P298)
Application No. 10/002,676)
Filed: October 31, 2001)
Title: METHOD FOR PLANARIZATION ETCH)
WITH IN-SITU MONITORING BY)
INTERFEROMETRY PRIOR TO RECESS ETCH)

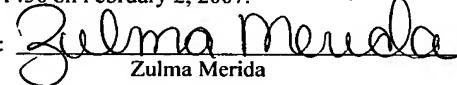
Examiner: Ahmed, Shamim

Group Art Unit: 1765

Date: February 2, 2007

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, Virginia 22313-1450 on February 2, 2007.

Signed: 
Zulma Merida

Separate Letter to the Official Draftsperson

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

Applicants hereby attach thirteen (13) sheets of formal drawings (Figures 1-13) for the above-referenced patent application. In the event the Draftsperson has any questions concerning the formal drawings, he or she is respectfully requested to contact the undersigned. If any fees are due in connection with the filing of these drawings, then please charge such fees to our Deposit Account No. 50-0805 (Order No. LAM2P298).

Respectfully submitted,
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